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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

28/2/04

Sergey A. Velichko et al.

CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING

Docket No.: 303.750US1
Filed: April 13, 2001
Examiner: Craig Steven Miller

Serial No.: 09/834751
Due Date: January 28, 2004
Group Art Unit: 2812

MS Non-Fee Amendment

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

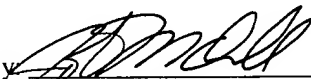
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We are transmitting herewith the following attached items (as indicated with an "X"):

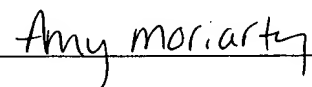
- ☒ A return postcard.
- ☒ An Amendment and Response (14 Pages).
- ☒ A Communication Concerning Related Applications (1 pg.).
- ☒ An Information Disclosure Statement (1 pg.), Form 1449 (1 pg.), and copies of 24 cited documents.
- ☒ A check in the amount of \$180.00 to cover the fee for consideration of Information Disclosure Statement under 97(c).

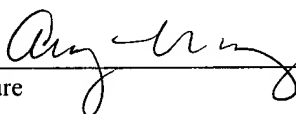
Please consider this a **PETITION FOR EXTENSION OF TIME** for sufficient number of months to enter these papers and please charge any additional fees or credit overpayment to Deposit Account No. 19-0743.

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.
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By 
Atty: John M. Dahl
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CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: MS Non-Fee Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 28th day of January, 2004.


Name


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(GENERAL)